

IGBT

TRENCHSTOPTM IGBT3 Chip SIGC28T60E

Data Sheet

Industrial Power Control

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TRENCHSTOP[™] IGBT3 Chip

Features:

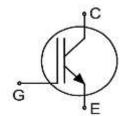
- 600V trench & field stop technology
- Low V_{CEsat}
- Low turn-off losses
- Short tail current
- Positive temperature coefficient
- Easy paralleling

Recommended for:

- Power modules
- Discrete components

Applications:

- Drives
- White goods
- Resonant applications



Chip Type	V _{CE}	I Cn	Die Size	Package
SIGC28T60E	600V	50A	6.57mm x 4.20mm	Sawn on foil

Mechanical Paramet	ers			
Die size		6.57 x 4.20		
Emitter pad size		See chip drawing	mm ²	
Gate pad size		0.82 x 1.52	IIIM	
Area total	27.59			
Silicon thickness		70	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	974		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is recommended not to consume the Ni layer comportation process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		AI, ≤500μm		
Reject ink dot size		∅ 0.65mm; max. 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C	– 25°C	
(<6 months)	for open MBB bags	Acc. IEC 62258-3; Section 9.4 Storage Envir	ronment.	



Maximum Ratings

In general, from reliability and lifetime point of view, the lower the operation junction temperature and/or the applied voltage, the greater the expected lifetime of any semiconductor device.

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T_{vj} =25°C	V _{CE}	600	V
DC collector current, limited by $T_{\rm vj\;max}^{\;\;\;1}$	I _C	-	А
Pulsed collector current, t_p limited by $T_{vj \max}^2$	I _{C,puls}	150	Α
Gate-emitter voltage	V_{GE}	±20	V
Virtual junction temperature	$T_{\rm vj}$	-40 +175	°C
Short circuit data $^{1/2/3}$ V_{GE} =15V, V_{CC} =360V, T_{vj} =150°C	$t_{ m sc}$	6	μs
Reverse bias safe operating area (RBSOA) ²	<i>I</i> c,max = 100A, <i>V</i> cEmax = 600V, <i>T</i> vj ≤ 150°C		

Static Characteristics (tested on wafer), T_{vj}=25°C

Parameter	Symbol	Conditions	Value			Unit
- and an elei	Symbol	Symbol Conditions		typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V, I_{C} =4mA	600	-	-	
Collector-emitter saturation voltage	V _{CEsat}	$V_{\rm GE}$ =15V, $I_{\rm C}$ =50A	1.05	1.45	1.85	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =0.8mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	$V_{CE} = 600 \text{V}, \ V_{GE} = 0 \text{V}$	-	-	2.6	μA
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$	-	ı	600	nA
Integrated gate resistor	$r_{\rm G}$			none		Ω

Electrical Characteristics 2

Parameter	Symbol	Conditions	Value			Unit
rarameter	Symbol	Conditions	min.	typ.	max.	Ullit
Input capacitance	C _{ies}	V _{CE} =25V, V _{GE} =0V, <i>f</i> =1MHz	ı	3140	1	
Output capacitance	Coes		-	200	-	pF
Reverse transfer capacitance	C _{res}	<i>T</i> _{vj} =25°C	-	93	-	

¹ Depending on thermal properties of assembly.

² Not subject to production test - verified by design/characterization.

³ Allowed number of short circuits: <1000; time between short circuits: >1s.



Further Electrical Characteristics

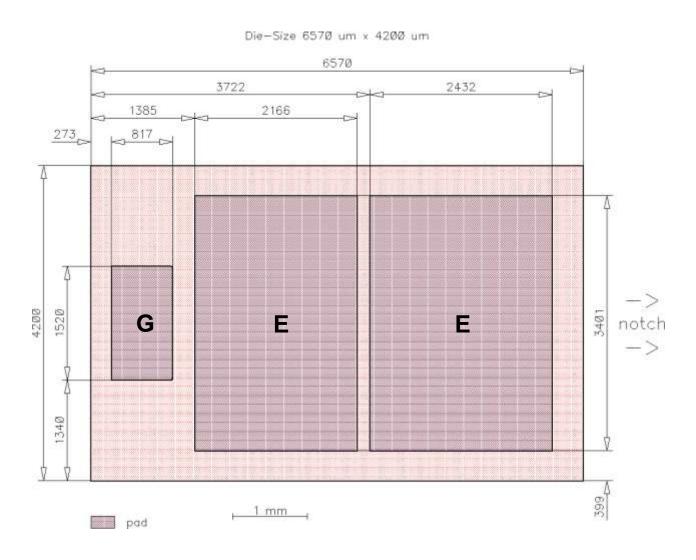
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	-	-
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L7561L, L7561T 5 Rev. 2.1, 19.07.2017



Chip Drawing



E = Emitter

G = Gate



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description	
AQL 0.65 for visual inspection according to failure catalogue	
Electrostatic Discharge Sensitive Device according to MIL-STD 883	

Revision History

Revision	Subjects (major changes since last revision)	Date
2.1	Final data sheet	19.07.2017

Relevant Application Notes					



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